

| L Number | Hits | Search Text | DB | Time stamp |
|----------|--------|---|--------------------|------------------|
| 1 | 1 | ("20030030084").PN. | USPAT; US-PGPUB | 2003/06/13 16:09 |
| 2 | 33869 | sem or "scanning electron microscope" | USPAT; US-PGPUB | 2003/06/13 16:09 |
| 3 | 466764 | semiconductor or "integrated circuit" or microelectronic or IC | USPAT; US-PGPUB | 2003/06/13 16:12 |
| 4 | 939 | (sem or "scanning electron microscope") with (semiconductor or "integrated circuit" or microelectronic or IC) | USPAT; US-PGPUB | 2003/06/13 16:12 |
| 5 | 745129 | intermediate | USPAT; US-PGPUB | 2003/06/13 16:12 |
| 6 | 5 | ((sem or "scanning electron microscope") with (semiconductor or "integrated circuit" or microelectronic or IC)) with intermediate | USPAT; US-PGPUB | 2003/06/13 16:14 |
| 7 | 308469 | testing | USPAT; US-PGPUB | 2003/06/13 16:14 |
| 8 | 33 | testing with ((sem or "scanning electron microscope") with (semiconductor or "integrated circuit" or microelectronic or IC)) | USPAT; US-PGPUB | 2003/06/13 16:23 |
| 9 | 68756 | cmp or polishing | USPAT; US-PGPUB | 2003/06/13 16:23 |
| 10 | 354271 | trench or recess | USPAT; US-PGPUB | 2003/06/13 16:23 |
| 11 | 13814 | conformal | USPAT; US-PGPUB | 2003/06/13 16:24 |
| 12 | 43 | (cmp or polishing) with (trench or recess) with conformal | USPAT; US-PGPUB | 2003/06/13 16:24 |
| - | 65379 | 438/\$.ccls. | USPAT; US-PGPUB | 2003/06/01 18:14 |
| - | 463378 | semiconductor or ic or "integrated circuit" or microelectronic | USPAT; US-PGPUB | 2003/05/29 17:11 |

→ protecting / protect\$3 with CMP

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| 11 | 13814 | conformal | USPAT; US-PGPUB | 2003/06/13 16:24 |
| 12 | 43 | (cmp or polishing) with (trench or recess) with conformal | USPAT; US-PGPUB | 2003/06/13 16:39 |
| 13 | 2296 | protect\$3 with (cmp or polishing) | USPAT; US-PGPUB | 2003/06/13 16:40 |
| 14 | 1443 | (semiconductor or "integrated circuit" or microelectronic or IC) and (protect\$3 with (cmp or polishing)) | USPAT; US-PGPUB | 2003/06/13 16:40 |
| 15 | 687 | (trench or recess) and ((semiconductor or "integrated circuit" or microelectronic or IC) and (protect\$3 with (cmp or polishing))) | USPAT; US-PGPUB | 2003/06/13 16:40 |
| 16 | 139 | conformal and ((trench or recess) and ((semiconductor or "integrated circuit" or microelectronic or IC) and (protect\$3 with (cmp or polishing)))) | USPAT; US-PGPUB | 2003/06/13 16:40 |
| - | 65379 | 438/\$.ccls. | USPAT; US-PGPUB | 2003/06/01 18:14 |
| - | 463378 | semiconductor or ic or "integrated circuit" or microelectronic | USPAT; US-PGPUB | 2003/05/29 17:11 |